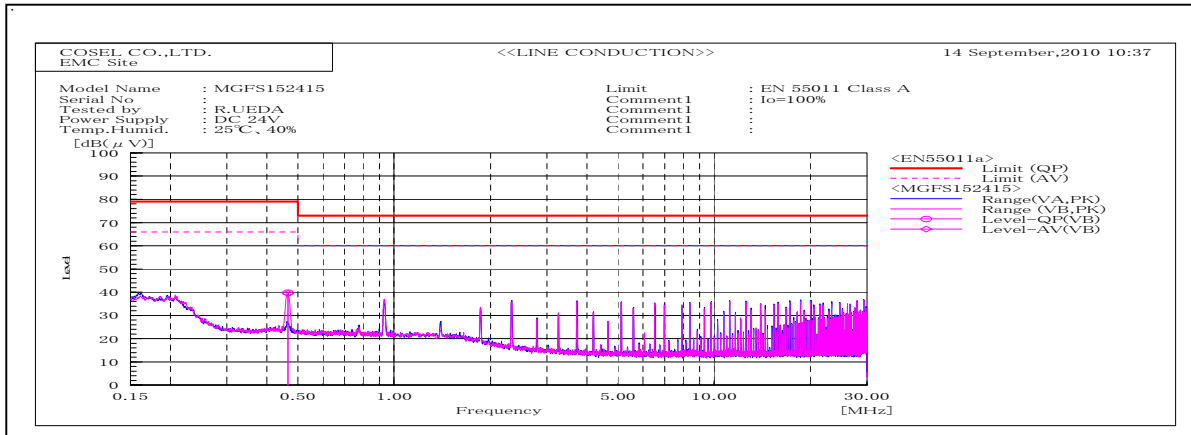
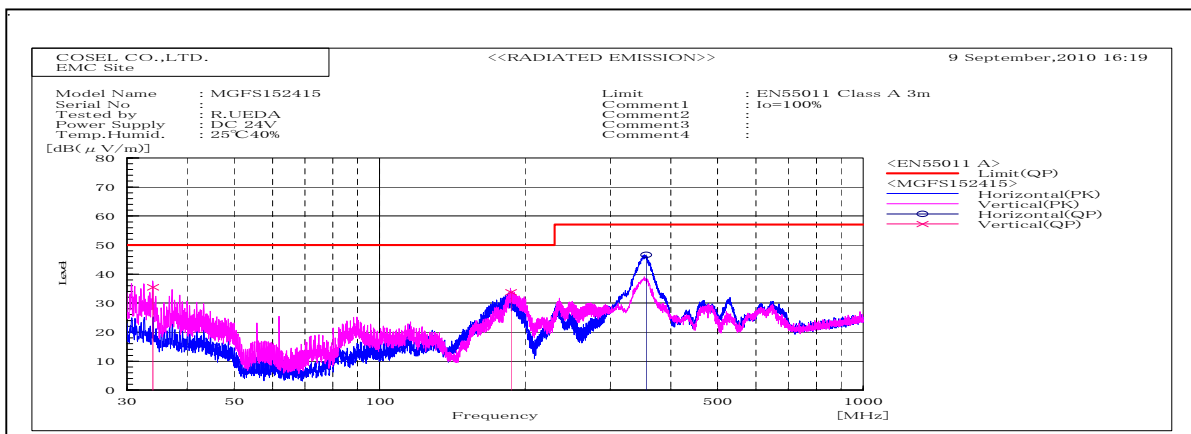


DATA SHEET		Date	21-Sep-10
Model	MGFS152415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Ueda



Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.4652		VB	29.8	29.4	10	39.8	39.4	79	66	39.2	26.6	Pass	

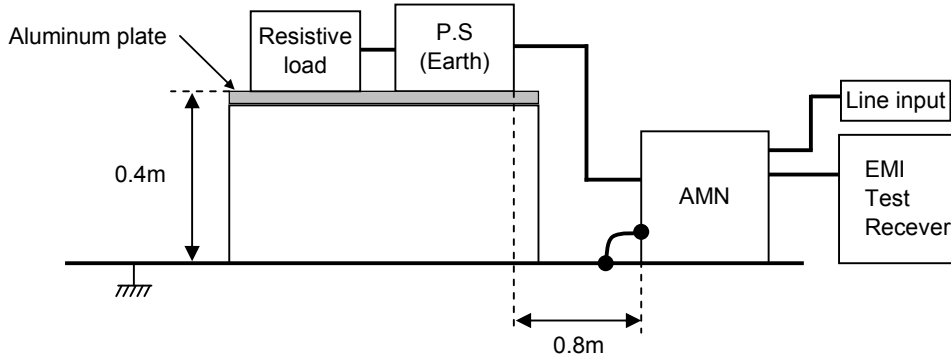


Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP		QP	QP						
33.974	V	Stable	50.9	-15.5	35.4	50	14.6	Pass	105	43			
186.884	V	Stable	56	-22.2	33.8	50	16.2	Pass	136	264			
355.927	H	Stable	62.7	-16.1	46.6	57	10.4	Pass	110	7			

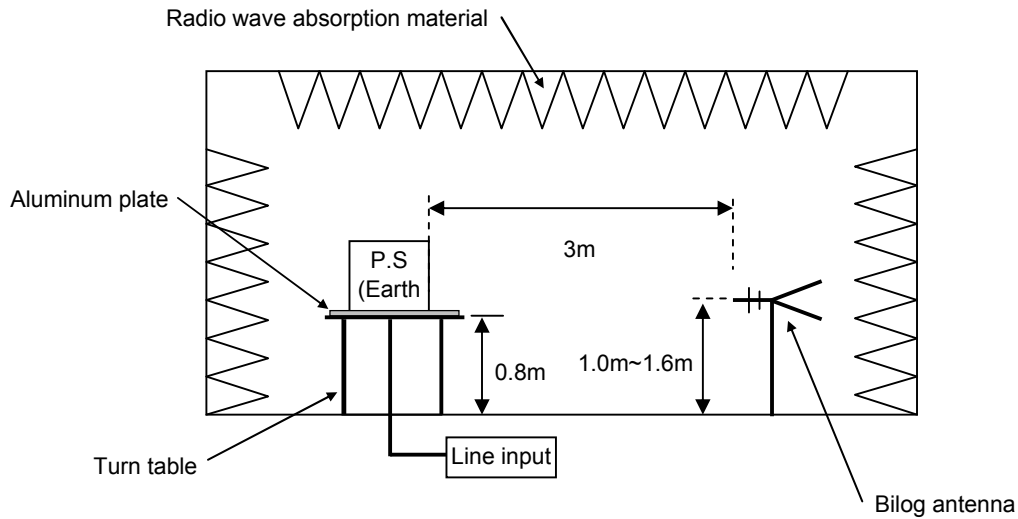
**DATA SHEET**

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

**1. Line conduction**



**2. Radiated emission**



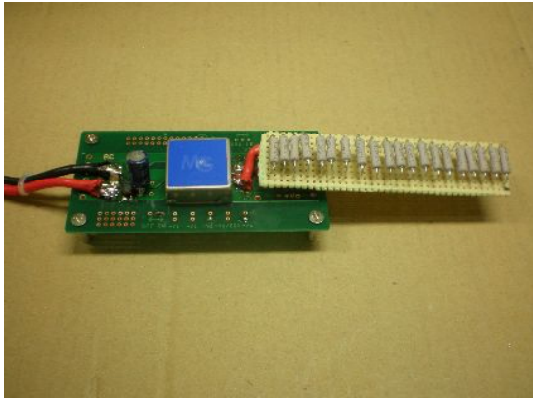


Conditions

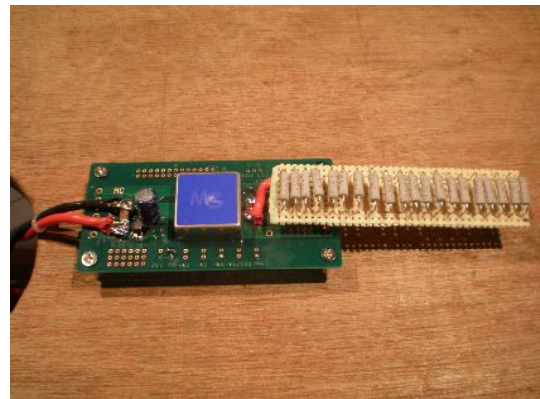
Test : EMI  
 Model Name : MGFS1524□□/MGFW1524□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

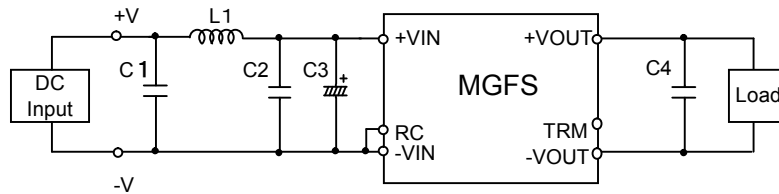


Fig.1 Testing circuitry 1

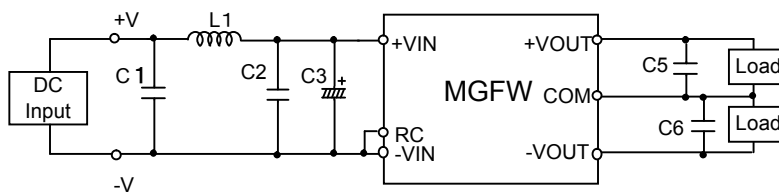


Fig.2 Testing circuitry 2

L1	: 0.5uH	CI4C-0R5	(KORIN ELECTRONICS)
C1,C2	: 50V 6.8 μ F	C4532X7R1H685MT	(TDK)
C3	: 50V 100 μ F	LXZ50VB100M	(NIPPON CHEMI-CON)
C4,C5,C6	: 25V 22 μ F	CM32X5R226K25A	(KYOCERA)